FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 2933SE-11-CIP-2 SERIAL NO. 09/037,674

INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)

ATTY. DOCKET NO. 2933SE-11-CIP-2	09/037,674
APPLICANT MIZUHARA et a	ι.
FILING DATE March 9, 1998	GROUP ART 2814

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB Class	FILING DATE IF APPROP.
ON	.AA	5,855,962	1/5/99	COTE et al.	B05D3	02	···
oN_	АВ	5,817,582	10/6/98	MANIAR	H01L 21	469	
0~	AC	5,569,618	10/29/96	MATSUBARA	H01L 21	8242	
ON	AD	5,186,745	2/16/93	MANIAR	c090 183	06	
							

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB Class	FILING DATE IF APPROP.
0~	AA	4,962,052	10/9/90	ASAYAMA et al.	437	31	
0~	AB	5,930,624	7/27/99	MURATA et al.	438	253	

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ON	AA	62-60242	3/16/87	Japan	H01L21	88		X
2N	AB	1-199456	8/10/89	Japan	H01L21	90		х
ON	AC	2-7451	1/11/90	Japan	H01L21	90		х
0~	AD	2-26055	1/29/90	Japan	H01L21	90		х
0N	AE	2-253643	10/12/90	Japan	H01L21	90		х
ON	AF	3-101130	4/25/91	Japan	H01L21	314		x
0~	AG	4-234149	8/21/92	Japan	H01L21	90		х
ON	АН	4-317358	11/9/92	Japan	H01L21	90		x
2N	AI	5-74963	3/26/93	Japan	H01L21	90		x
0~	AJ	5-198523	8/6/93	Japan	H01L21	265		х
ON	AK	6-275229	9/30/94	Japan	H01J37	317		X

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0N	AL	6-349950	12/22/94	Japan	H01L21	90	х
2N	АМ	7-99195	4/11/95	Japan	H01L21	3205	х
IN	AN	8-17770	1/19/96	Japan	H01L21	304	 x
on	AO	8-64561	3/8/96	Japan	H01L21	304	х

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROP.
on	AA	5,084,412	1/92	Nakasaki	257	762	
IN	AB	5,479,054	12/95	Tottori	257	760	
2N	AC	5,753,975	5/98	Matsuno	257	760	

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROP.
0~	AA	5,153,680	10/06/92	NAITO ET AL.	357	8	
0/	AB	3,747,203	07/24/73	SHANNON	29	578	
0N	AC	5,166,768	11/24/92	ITO	257	523	

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$\theta \sim AD$	4,218,495 A1	12/10/92	GERMANY			> x		
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROP.
0~	AA	4,676,867	06/30/87	Elkins et al.	156	643	
ON	АВ	4,775,550	10/04/88	Chu et al.	427	38	
ON	AC	4,885,262	12/05/89	Ting et al.	437	231	
0~	AD	4,983,546	01/08/91	Hyun et al.	437	231	
dN	AE	5,003,062	03/26/91	Yen	437	231	
0~	AF	5,106,787	04/21/92	Yen	437	231	
DN	AG	5,192,697	03/09/93	Leong	437	37	
0N	AH	5,352,630	10/04/94	Kim et al.	437	195	
0N	AI	5,429,990	07/04/95	Liu et al.	437	190	
0~	LA	5,496,776	03/05/96	Chien et al.	437	231	
0~	AK	5,549,786	08/27/96	Jones et al.	156	662.1	

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0~	AL	1-307247	12/12/89	Japan				x
0~	АМ	5-226334	3/9/93	Japan				х
2N	AN	2-101532	8/13/90	Japan				х
$\mathcal{N}_{\mathcal{G}}$	AO	2-235358	9/18/90	Japan				х

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0~	AP	Wang et al., "A Study of Plasma Treatments on Siloxane SOB," IEEE VMIC Conference, June 7-8, 1994, pp. 101- 107.
0N	AQ	Chiang et al., "Defects Study on Spin on Glass Planarization Technology, IEEE VMIC Conference, June 15-16, 1987, pp. 404-412.
11	AR	Lai-Juh Chen, et al., "Fluorine-Implanted Treatment (FIT) SOG for the Non-Etchback Intermetal Dielectric," IEEE VMIC Conference, June 7-8, 1994, pp. 81-86.
ON	AS	Moriya et al., "Modification Effects in Ion-Implanted SiO₂ Spin-on-Glass," <u>J. Electrochem. Soc.</u> , Vol. 140, No. 5, May 1993, pp. 1442-1450.
0,1	AT	Matsuura et al., "An Advanced Interlayer Dielectric System with Partially Converted Organic SOG Using Plasma Treatment," IEEE VMIC Conference, June 8-9, 1993, pp. 113-115.
0~	AU	Ishida et al., "Mechanism for AlSiCu Alloy Corrosion," <u>Jpn. J. Appl. Phys.</u> , Vol. 31 (1992), pp. 2045-2048.
<i>∂</i> N	AV	Doki et al., "Moisture-Blocking Mechanism of ECR-Plasma," IEEE VMIC Conference, June 7-8, 1994, pp. 235-139.
01	AW	Shimokawa et al., "Suppression of MOSFET hot carrier degradation by P-SiO underlayer," <u>The Institute of</u> <u>Electronics, Information and Communication Engineers</u> ," Technical Report of IEICE, SDM92-133 (1992-12), pp. 89-94.
0 ~/	АХ	Murase et al., "Dielectric Constant of Silicon Dioxide Deposited by Atmospheric-Pressure Chemical Vapor Deposition Using Tetraethylorthosilicate and Ozone," <u>Jpn. J. Appl. Phys.</u> , Vol. 33 (1994), pp. 1385-1389.

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ON	AA	5,153,680	10/06/92	NAITO ET AL.	357	8	
0~	АВ	3,747,203	07/24/73	SHANNON	29	578	
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